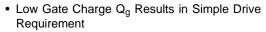


N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMA	RODUCT SUMMARY				
V _{DS} (V)	650)			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	4			
Q _g (Max.) (nC)	11				
Q _{gs} (nC)	2.3	3			
Q _{gd} (nC)	5.2	2			
Configuration	Sing	le			

FEATURES

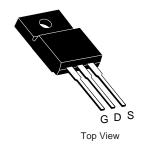


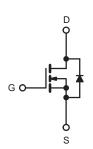


• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS To	c = 25 °C, un	less otherw	ise noted		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V_{DS}	650	V	
Gate-Source Voltage		V_{GS}	± 30	V	
Continuous Drain Currente	V_{GS} at 10 V $T_C = 25 ^{\circ}C$			2.0	
Continuous Drain Current	VGS at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	I _D	1.28	Α
Pulsed Drain Current ^a		I _{DM}	8		
Linear Derating Factor			0.48	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	165	mJ	
Repetitive Avalanche Current ^a			I _{AR}	2	Α
Repetitive Avalanche Energy ^a			E _{AR}	6	mJ
Maximum Power Dissipation $T_C = 25 ^{\circ}C$		P_{D}	25	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.8	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature) ^d for 10 s			300		
Mounting Torque	6 32 or M	6-32 or M3 screw		10	lbf ⋅ in
	0-32 OF IVIS SCIEW			1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 24 mH, R_G = 25 Ω , I_{AS} = 3.2 A (see fig. 12).
- c. $I_{SD} \le 3.2$ A, $dI/dt \le 90$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RAT	RMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	=	2.1	C/VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	V _{GS} :	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA ^d	-	670	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 30 V	ı	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1 A b	-	4.0	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 50 V, I _D = 1 A	3.9	-	-	S
Dynamic					•		
Input Capacitance	C _{iss}		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		417	-	
Output Capacitance	C _{oss}	1			45	-	
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	-	5	-	- pF -
Output Capacitance	C _{oss}	., .,	$V_{DS} = 1.0 \text{ V}, f = 1.0 \text{ MHz}$ $V_{DS} = 520 \text{ V}, f = 1.0 \text{ MHz}$	-	912 26	-	
Effective Output Capacitance	C _{oss} eff.	$V_{GS} = 0 V$	$V_{DS} = 320 \text{ V}, T = 1.0 \text{ Will 12}$ $V_{DS} = 0 \text{ V to } 520 \text{ V}^{c}$	-	42	-	
Total Gate Charge	Qg			-	-	11	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 1.2 \text{ A}, V_{DS} = 400 \text{ V}$ see fig. 6 and 13 ^b	-	-	2.3	nC
Gate-Drain Charge	Q_{gd}			-	-	5.2	
Turn-On Delay Time	t _{d(on)}			-	14	-	1
Rise Time	t _r		= 325 V, I _D = 1.2A	-	20	-	
Turn-Off Delay Time	t _{d(off)}	$R_{G} =$	$R_G = 9.1 \Omega$, $R_D = 62 \Omega$, see fig. 10^b		34	-	ns -
Fall Time	t _f				18	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	MOSFET symbol showing the integral reverse p - n junction diode		-	2	A
Pulsed Diode Forward Current ^a	I _{SM}				-	8	
Body Diode Voltage	V _{SD}	T _J = 25 °C	T _J = 25 °C, I _S = 3.2 A, V _{GS} = 0 V ^b		-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.2 A, dI/dt = 100 A/µs ^b		-	180	230	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

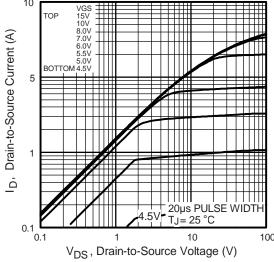
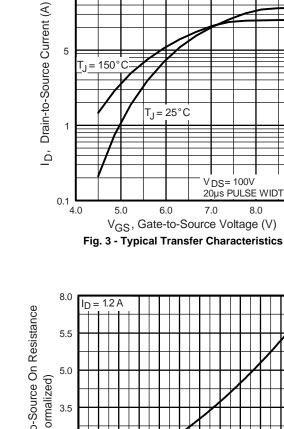


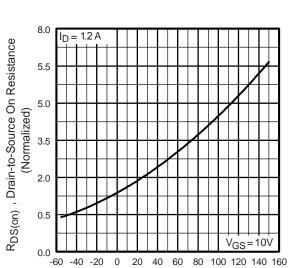
Fig. 1 - Typical Output Characteristics



 $T_{.J} = 150^{\circ}C$

10 VGS TOP 15V 10V 8.0V 7.0V 6.0V 5.5V 5.0V BOTTOM 4.5V Drain-to-Source Current (A) 5 ث 20µs PULSE WIDTI T_J= 150 °C 0.1 100 V_{DS}, Drain-to-Source Voltage (V)

Fig. 2 - Typical Output Characteristics



 $T_J = 25^{\circ}C$

6.0

 V_{GS} , Gate-to-Source Voltage (V)

V_{DS}= 100V

20µs PULSE WIDTH

T_J, Junction Temperature (°C) Fig. 4 - Normalized On-Resistance vs. Temperature



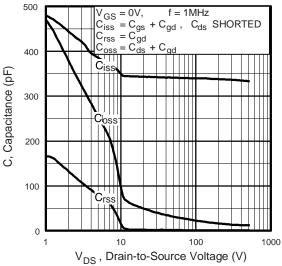


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

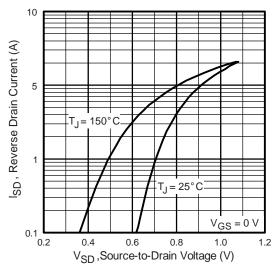


Fig. 7 - Typical Source-Drain Diode Forward Voltage

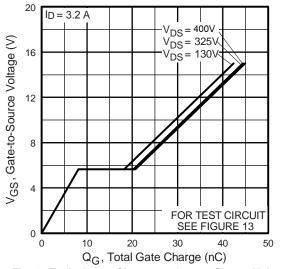


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

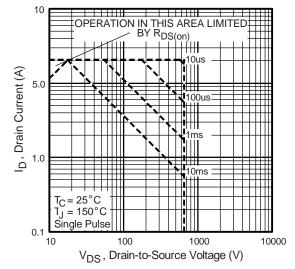


Fig. 8 - Maximum Safe Operating Area



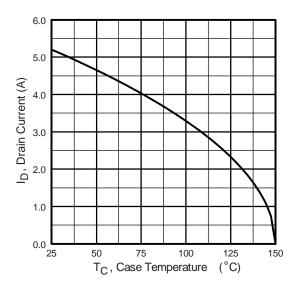


Fig. 9 - Maximum Drain Current vs. Case Temperature

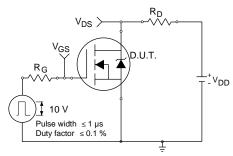


Fig. 10a - Switching Time Test Circuit

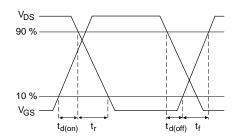


Fig. 10b - Switching Time Waveforms

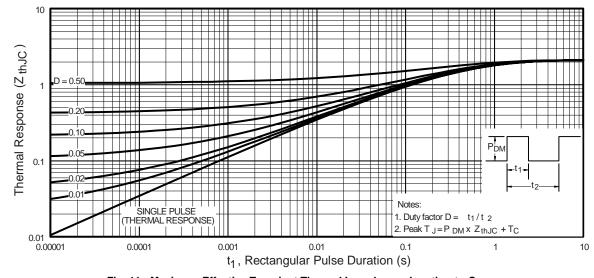


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

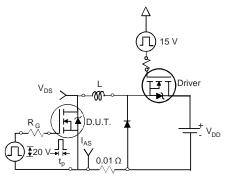


Fig. 12a - Unclamped Inductive Test Circuit

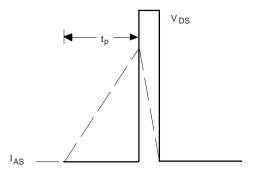


Fig. 12b - Unclamped Inductive Waveforms



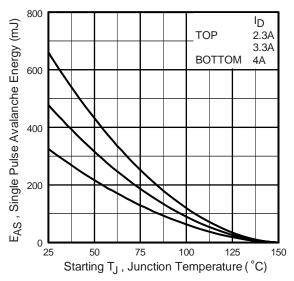


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

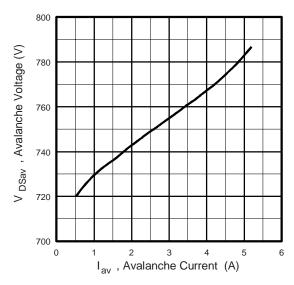


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

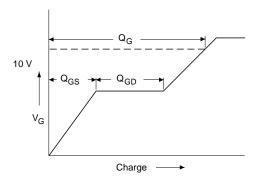


Fig. 13a - Basic Gate Charge Waveform

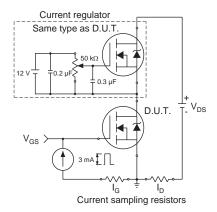
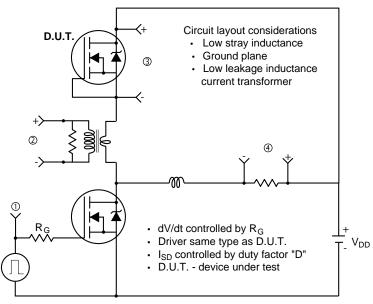
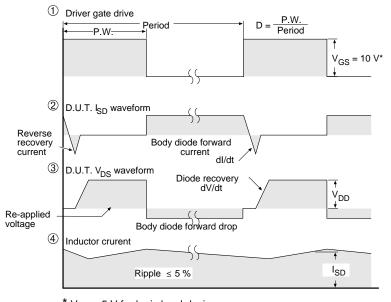


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



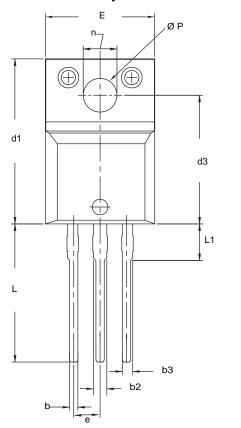


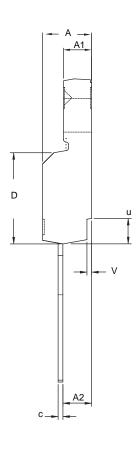
* $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)





DIM.	MILLIN	METERS	INC	HES
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.

- 5. No chipping or package damage.

8



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